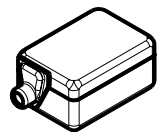
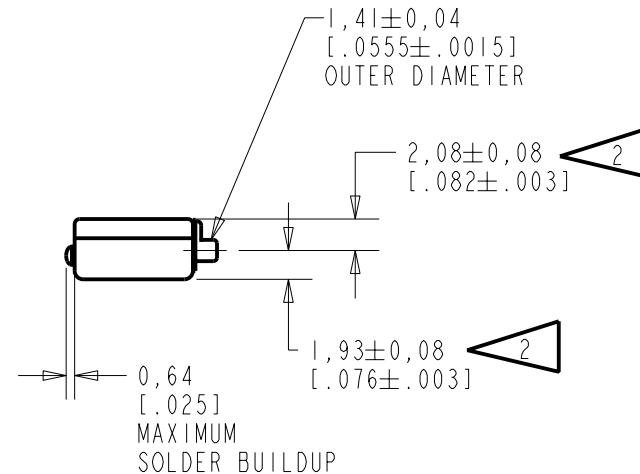
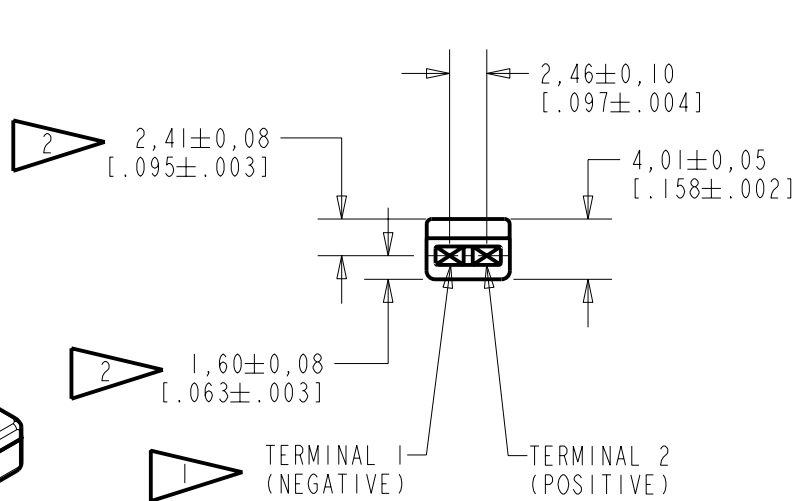


NOTES:

- 1 A POSITIVE GOING VOLTAGE AT TERMINAL 2, RELATIVE TO TERMINAL 1, CAUSES A DECREASE IN PRESSURE AT THE SOUND OUTLET.
- 2 LOCATED FROM TWO SURFACES FOR CUSTOMER CONVENIENCE. ONLY APPLICABLE FROM ONE SURFACE, NOT TO BE USED TOGETHER. HORIZONTAL LOCATION FOR TERMINAL CENTERED TO ±0,17 [.007].

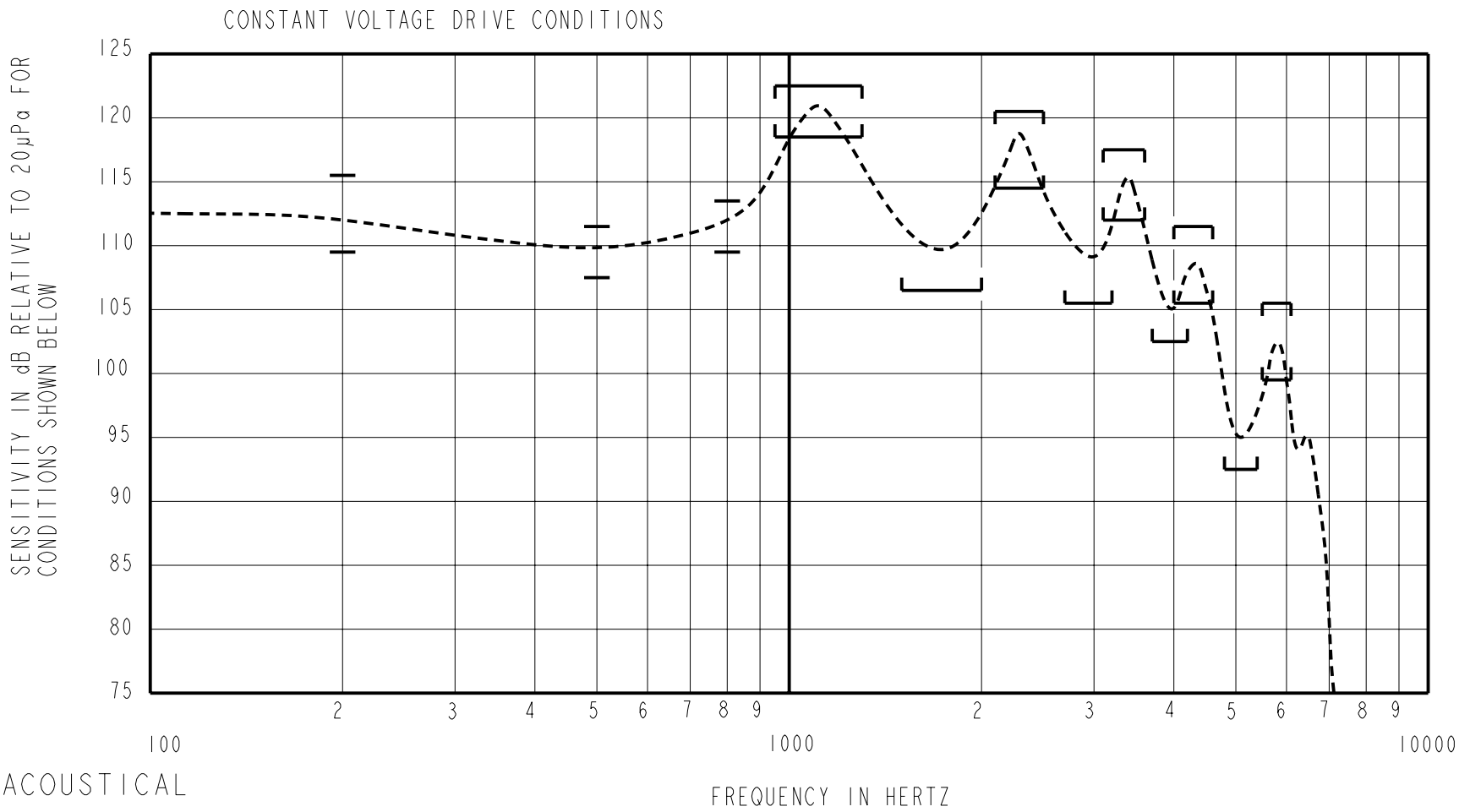


NOMINAL WEIGHT
.66 GRAM

DIMENSIONS IN MILLIMETERS [INCHES]

KNOWLES ELECTRONICS
ITASCA, ILLINOIS U.S.A.

Revision	C.O. #	Implementation Date	RELEASE LEVEL	REVISION
A	CI0104592	7-14-06	Released	A
SCALE: 2:1			DR. BY	DATE
DO NOT SCALE DRAWING			AB	7-14-06
TITLE: RECEIVER			CK. BY	DATE
OUTLINE DRAWING			CRG	7-19-06
EF-30037-000			APP. BY	DATE
SHT 1.1			GJP	7-19-06



SENSITIVITY
 DEVICE WILL PRODUCE THE SPL LISTED BELOW UNDER TEST CONDITIONS DESCRIBED IN TABLE 3.
 NOMINAL SENSITIVITY AT 500 Hz IS dB RELATIVE TO 20μPa. ALL OTHER VALUES
 IN dB RELATIVE TO THE SENSITIVITY AT 500 Hz.

FREQUENCY (Hz)	MINIMUM	NOMINAL	MAXIMUM
200	0.0	+3.0	+6.0
500	-2.0	109.5	+2.0
800	0.0	+2.0	+4.0
950-1300	+9.0	+11.0	+13.0
1500-2000	-3.0	-	-
2100-2500	+5.0	+8.0	+11.0
2700-3200	-4.0	-	-
3100-3600	+2.5	+5.5	+8.5
3700-4200	-7.0	-	-
4000-4600	-4.0	-1.0	+2.0
4800-5400	-17.0	-	-
5500-6100	-10.0	-7.0	-4.0

PORT LOCATION: IS

TABLE 1
 TOTAL HARMONIC DISTORTION
 DEVICE WILL NOT EXCEED TOTAL HARMONIC DISTORTION LEVELS LISTED BELOW.

FREQUENCY (Hz)	AC DRIVE (V rms)	DC BIAS (mA)	LIMIT (%)
500	0.118	0	5
500	0.210	0	10

TABLE 2
 TEST CONDITIONS

NOMINAL SOURCE VOLTAGE	0.118 V rms, 0 mA DC BIAS
SOURCE IMPEDANCE	<1 Ohm
TUBING	8mm x 1mm ID + 28mm x 1.5mm ID EAR HOOK SIMULATOR + 25mm x 2mm ID TUBE + 18mm x 3mm ID TUBE
COUPLER CAVITY	2 CM ³ , SIMULATED ANSI S3.7 TYPE HA-3 (IEC 126)

TABLE 3
 ELECTRICAL

DC RESISTANCE	15 Ohms ± 10%
IMPEDANCE @ 500 Hz	40 Ohms ± 15%
IMPEDANCE @ 1kHz	98 Ohms ± 15%

TABLE 4
 ISOLATION: CASE WILL BE ELECTRICALLY ISOLATED FROM THE COIL CIRCUIT.

Revision	C.O. #	Implementation Date	RELEASE LEVEL	REVISION
			Released	A
A	C10104592	7-14-06		

KNOWLES ELECTRONICS ITASCA, ILLINOIS U.S.A.	WHEN TEST LIMITS ARE USED TO ESTABLISH INCOMING INSPECTION ACCEPTANCE/REJECTION CRITERIA, CORRELATION OF TEST EQUIPMENT WITH KNOWLES IS ALSO REQUIRED FOR ELIMINATION OF EQUIPMENT AND TEST METHOD VARIATION		DR. BY	DATE
	RECEIVER	EF-30037-000	AB	7-14-06
			CRG	7-19-06
	PERFORMANCE SPECIFICATION	SHT 2.1	APP. BY	DATE
		GJP	7-19-06	